GMW

Webinar: Integrated Probe Card Solutions for Magnetic Testing



Lead Magnet Scientist GMW Associates

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CEO Celadon Systems



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Agenda

- Celadon On-Wafer Probe Solutions and Integration for Magnetic Testing Presented by Karen Amendariz, Celadon Systems
- Spintronic On-Wafer Testing: An Integrated Solution Presented by Tom King, GMW Associates
- Questions and Answers Karen Amendariz and Bill Funk of Celadon Systems, Tom King of GMW Associates



GMW – CELADON INTEGRATION WEBINAR

KAREN ARMENDARIZ

August 25th, 2020



CELADON SYSTEMS – KNOWN FOR INNOVATIVE ON-WAFER PROBE SOLUTIONS IN EXTREME ENVIRONMENTS



- Celadon's core competencies:
 Probe cards, Cables and Adaptors
- Technology: Advanced Cantilever
- Celadon's core values: Integrity, Innovation, Invention, Dedication
- Celadon has 57 Patents and 15 Pending Patents.

- Celadon has been in business 23 years. Celadon products are used by ~90% of semiconductor companies worldwide in addition to other applications like medical, space and defense.
- Celadon is a US based company: All of our engineering, manufacturing and repair is done in Burnsville, Minnesota.
- Celadon has a support center for PMs in Taiwan.





THREE IMPORTANT FACTS TO REMEMBER ABOUT CELADON SYSTEMS

I - Technology: ADVANCED CANTILEVER

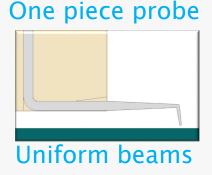
- => Near Vertical, 0-9 degrees, with a "tunable scrub"
- => Controlled scrub mark and gram force

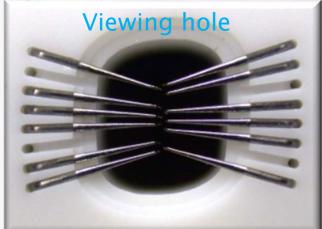
Our Advanced Cantilever offers customers the BEST OF BOTH WORLDS

- Cantilever Technology:
 - Familiar technology, operators aren't afraid of it
 - Learning curve is short
 - Probe marks are visible
 - Rebuildable and Repairable

What is "ADVANCED" about our technology?

- The ability to probe very fine features due to our "tunable scrub" and our automated manufacturing processes with tight tolerances:
 - » Our Production customers are probing 25 micron pads successfully at room temperature
 - » Using the same card, our Lab customers are probing from -65C to 200C on ~30 micron pads.
- Low Leakage, our goal is to be invisible in your set up, offering products with less than 1fA.







II - Celadon's patented Crash Resistant Probe in Ceramic Technology[™] results in FEW rebuilds and alignments over the cards lifetime:

Celadon has a different model, we don't have repair centers all over the world, because we haven't needed them. We have one Repair Center located in Minnesota. Our cards are extremely durable and robust.

In total, Celadon only rebuilds about 25 cards a month for ALL territories
 with tens of thousands of active cards in the field.

 Most failures are handling related or occasionally due to a burnt pin versus being worn out.



We at Celadon are very serious about our probe card's durability. If you are interested in seeing how robust our cards are, we have some informative and entertaining videos online at <u>www.celadonsystems.com</u> demonstrating what happens when a Celadon card is crashed into a wafer, ran over, blown up, grilled, frozen or washed in a dishwasher - we simply brush the probes off using a Celadon toothbrush and start probing again. We hope you check out our videos!

III - Exceptionally Long Life - If you take care of your probe cards, you can expect millions of touch downs whether you are in the LAB, FAB or on the TEST FLOOR.

- Celadon Systems and Freescale Corp/NXP published a joint technical paper five years ago at SW Test on exceptional lifetime performance. At that time, they had achieved 13 million TDs using Celadon's VC20™.
- Customers have reported over 20 million touch downs on their probe cards. To prevent unplanned failures, most of our production customers intentionally rebuild at 10 million touch downs.

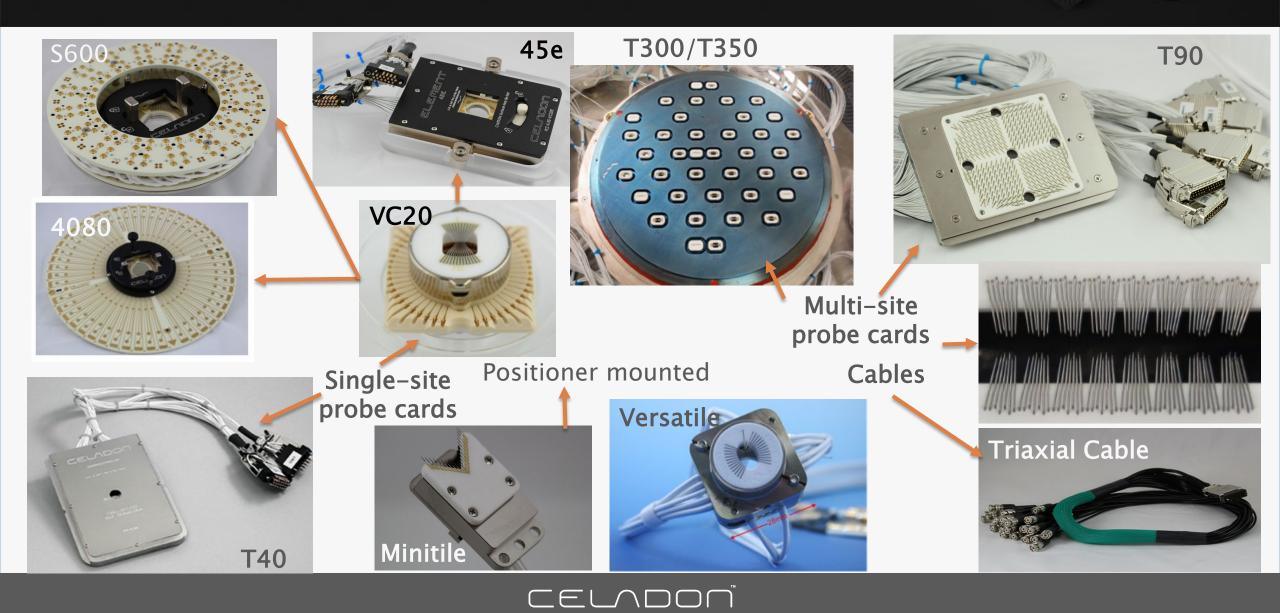


Celadon's goal for you is *Peace of Mind Probing* - we want your cards to work as intended, so they aren't "top of mind", so you can focus on other things.

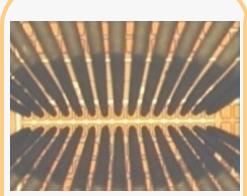
CELADON'S MARKET FOCUS



CELADON'S SINGLE-SITE AND MULTI-SITE PROBE CARD AND CABLE EXAMPLES



CELADON'S KEY DIFFERENTIATORS



Accurate Measurements Low noise, low leakage, high accuracy measurements Ultra Low Leakage Small sub-30µm pads



Extreme Temperature

Wide operating temperature

-65C to 600C 4, 7, 77 Kelvin

Versatile: Fixed and Adjustable Multi-Site

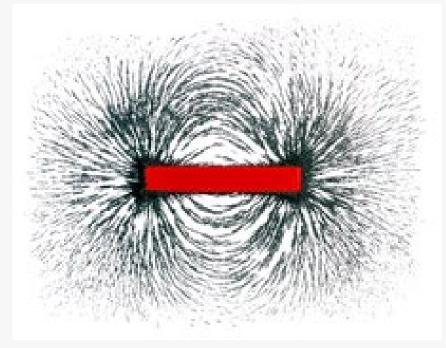
> Flexible, innovative solutions



Robust and Long Life

Low maintenance, low cost of ownership *Millions of touchdowns*







NON-FERROMAGNETIC PROBE CARD, EXAMPLE 1

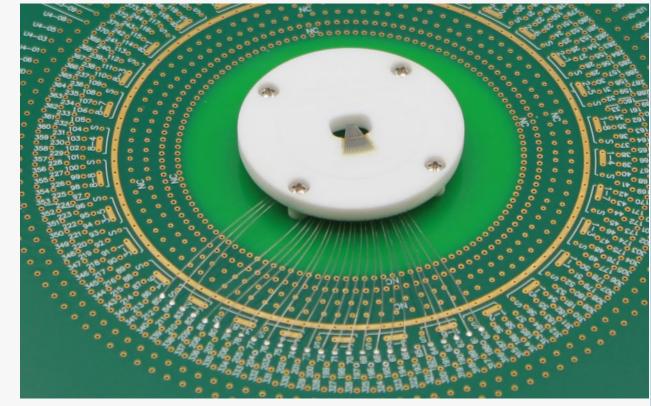
Customer unable to achieve thermal stability with existing MRAM probe card set up so they turned to Celadon

Successful implementation of a non-ferromagnetic probe card and Celadon overcame the following challenges:

- Accommodate existing GMW 5203 vertical magnet
- Total distance between top of probe card to tips ~13mm's which we achieved by adding a spacer
- Temperature range -40 to 150C
 - Achieved thermal stability on 35 micron pads

Magnet side





Wafer side

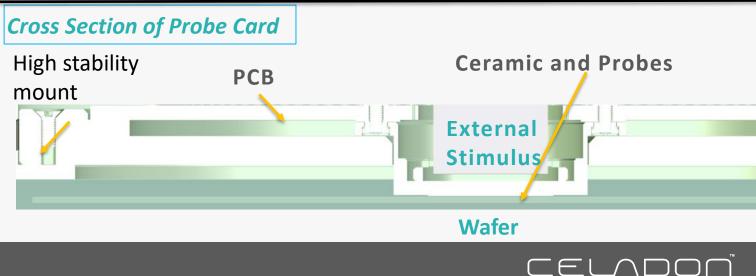


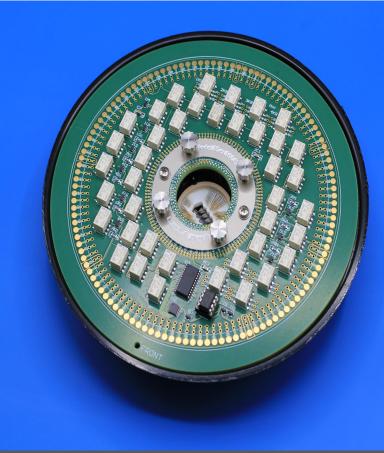
NON-FERROMAGNETIC PROBE CARD EXAMPLE 2

Customer was unable to achieve thermal stability with existing MRAM cards over temperature after working with several probe card suppliers, so they turned to Celadon.

Successful implementation of a non-ferromagnetic probe cards and Celadon overcame the following challenges:

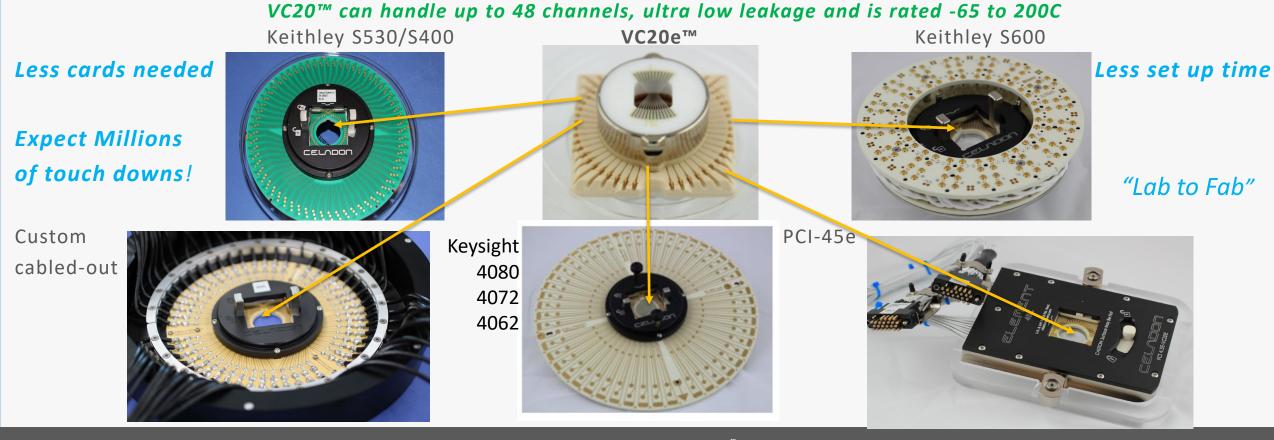
- Thermal Stability:
 - On 60 micron pads
 - Temperature testing: 150C (card rated to 200C)
- Very low profile stack up
 - Achieved by Celadon thinning ceramic to reduce thickness
- Lifetime performance is exceptional for this production application
- Millions of touch downs, few rebuilds over the years





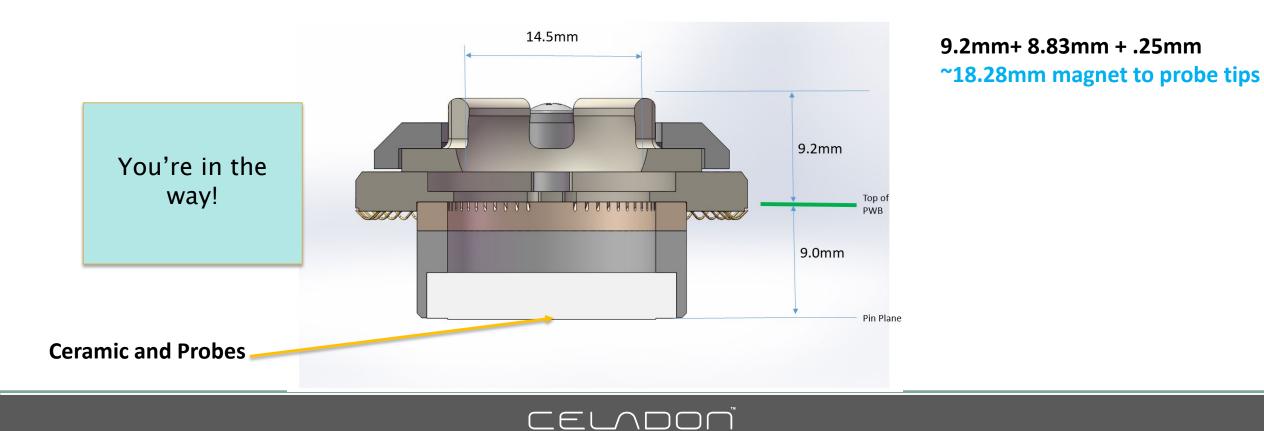
CELADON – GMW VERTICAL FIELD SOLUTION INTEGRATION, EXAMPLE 3

Several years back, Celadon and GMW Associates were requested to develop an integrated solution using the GMW 5203 vertical magnet coupled with the Celadon VC20e[™]. The VC20[™] is our most popular modular probe card because it offers many advantages over dedicated probe cards. First of all, it is quick change and can be shifted easily from one style board to another - *less than a minute change time using our Insertion Tool.*



CHALLENGES USING THE VC20™ IN A MAGNETIC SET UP

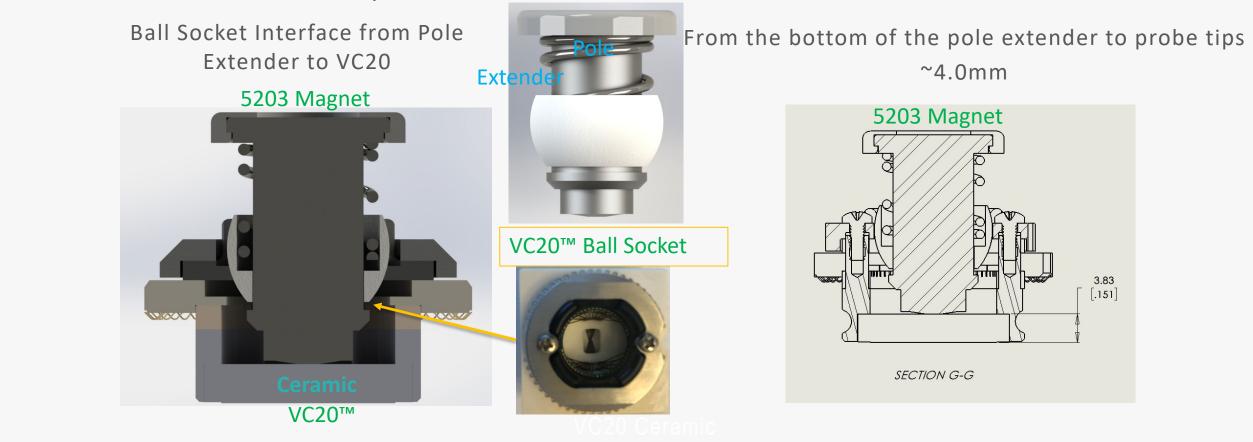
- The set up the customer desired was the VC20[™] plus Keysight 4080 motherboard. Using this setup "as is" prevented the GMW magnet from being close enough to the DUT to get the field density required.
- The challenge was to find a way to overcome the physical distance between the magnet and the DUT. Cross section of the VC20[™] Probe Card



DEVELOPMENT OF THE PATENTED MAGNETIC POLE EXTENDER

- To get the magnet close enough to the DUT to achieve customers required field, Celadon had to manufacture a solution that would extend the magnetic focal point of the 5203 vertical magnet lower and closer to the DUT.
- Celadon partnered with GMW Associates and developed a *Magnetic Pole Extender with a spring mechanism* and a process to create custom pole extenders going forward.
 - GMW used Celadon VC20[™] models and a simulated customer die to model and calculate the optimal shape of the Magnetic Pole Extender which Celadon used to manufacture it.
- Here is what is unique about this patented Pole Extender:
 - It snaps into the back of the non-ferromagnetic VC20[™] probe card.
 - We integrated a Spring Mechanism:
 - When the unit is turned on, it automatically shifts the pole extender to the 5203 magnet.
 - It absorbs dimensional variations of the test head and magnet within a specific range.
 - It prevents the pole extender from moving too quickly and slamming into the magnet face causing damage when the unit is turned on.

The 5302 vertical magnet rests as close as possible to the top of the VCOe[™] probe card with the Pole Extender in place.



FINAL INTEGRATION MODEL OF GMW 5203 VERTICAL MAGNET AND CELADON VC20™

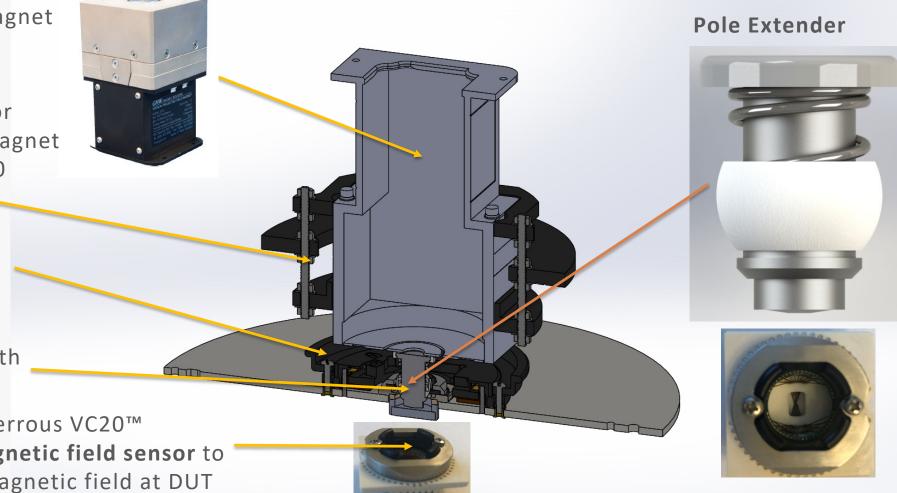
GMW 5203 Vertical Magnet

Celadon Docking Unit for mounting GMW 5203 magnet in Agilent/Keysight 4080 camera tunnel

Celadon Non-Ferrous Latch assembly

Celadon pole extender with spring compression

> Celadon Non-Ferrous VC20[™] including a magnetic field sensor to calibrate the magnetic field at DUT



Celadon and GMW Associates were requested to develop an integrated solution using the GMW 5201 magnet to produce a Horizontal Magnetic Field over a specific DUT.

- To fit the type of pole extender required for this request, Celadon and GMW agreed that GMW would calculate, design, and manufacture the 2x poles needed to produce the horizontal field the customer required.
- Celadon would design non-ferromagnetic MiniTiles[™], with a custom chassis to give the GMW poles mechanical clearance.

MiniTile[™] example

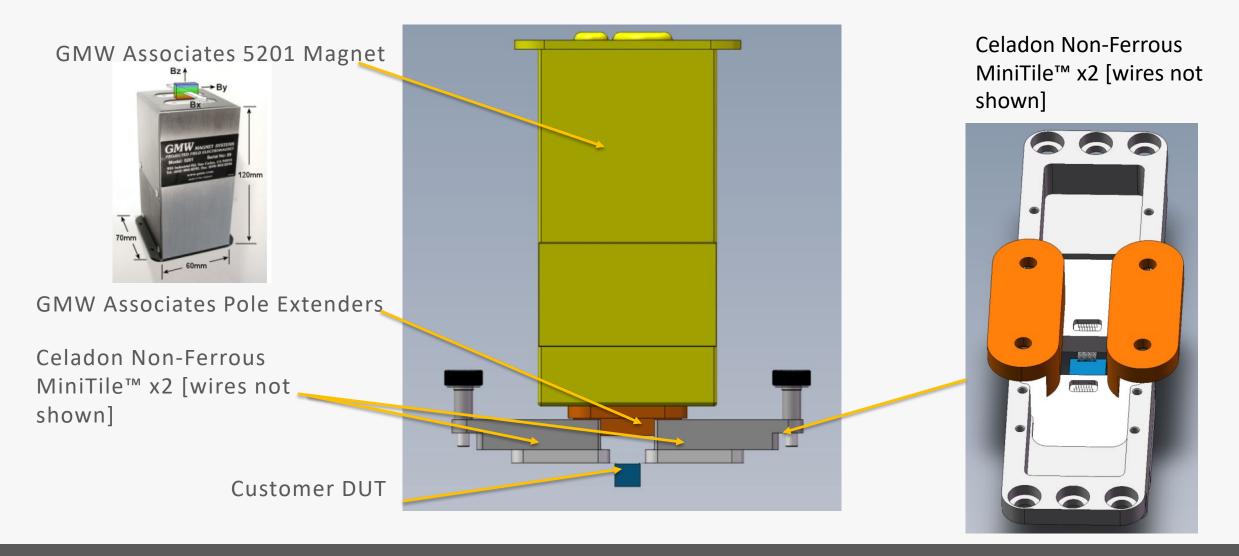


- MiniTiles[™] would be held by positioners with RF adapter arms from 2 sides.
- Probe card alignment:

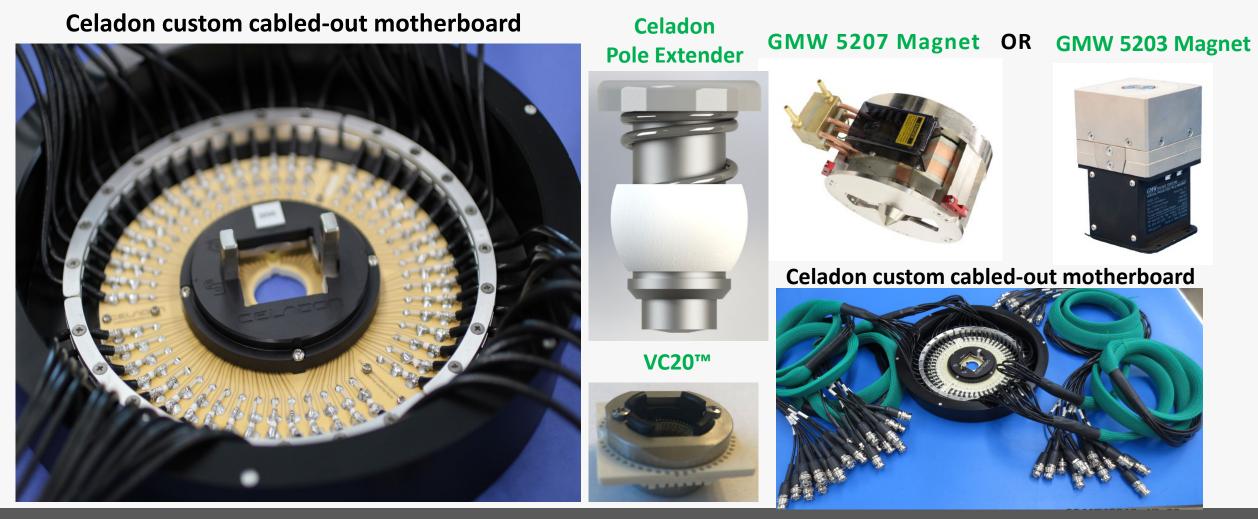
⇒Using an overhead microscope, perform the alignment, then when ready to probe and test, the microscope would be swapped with the GMW 5201 magnet.

- => With an upward looking camera, the magnet would remain
- in place during the probe card alignment process.

MODEL OF THE INTEGRATED 5201 MAGNET WITH CELADON MINITILES™



CABLED-OUT GMW 5203 OR 5207 MAGNETIC INTEGRATED VERTICAL SOLUTION, EXAMPLE 5





I hope you can see that Celadon and GMW have worked hard over the years and have streamlined the integration process. At this point, we have a collection of modular parts that we can easily bring together to create custom integrated solutions and we can do so very quickly.

Please reach out to us with your on-wafer magnetic testing challenges!



Thank you to the GMW Associates and Celadon Integration Team for all of their hard work to develop these innovative and well-needed solutions.

> Bill Funk, Celadon Systems Tom King, GMW Associates Garrett Tranquillo, Celadon Systems Brian Richter, GMW Associates



Spintronic On-Wafer Testing An integrated Solution

GMWAssociates

Presented by:

Tom King GMW Associates tom@gmw.com

GMW Associates

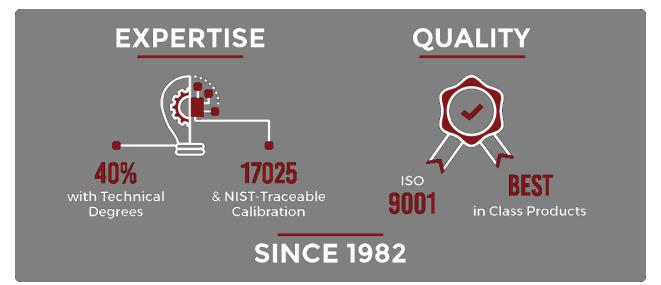
Products and Expertise

GMWAssociates

GMW Associates - Overview

GMW is the designer, integrator, and distributor of Magnetic Systems and Instrumentation based on Magnetics.

- Founded in 1982
- Staff of 20, over 40% with technical degrees
- Headquarters in San Carlos, California (30 miles from San Francisco)



Products and Services

Electromagnet Systems

- Dipole Magnets
- Projected Field Magnets
- High Uniformity Magnets
- Magnetic Modeling & Design

Instrumentation

- Magnetic Field Measurement
- Electric Current
 Measurement

Calibration and Service

- 17025 Accredited Calibration Lab
- Magnetic Field Mapping
- Magnetic Site Survey



GMW Associates – Electromagnet Systems

Complete Electromagnet Systems, Including:

- Electromagnet
- Chiller
- Power Supplies
- Control Software
- Magnetic Modelling and Custom Designs

Typical Applications:

- EPR
- Spintronics
- NV Centers
- Mössbauer
- FMR
- MOKE

- Neutron Beam Line
- Materials Research
- Low Resolution NMR
- Ion Implantation
- VSM



GMWAssociates

Integration with Celadon

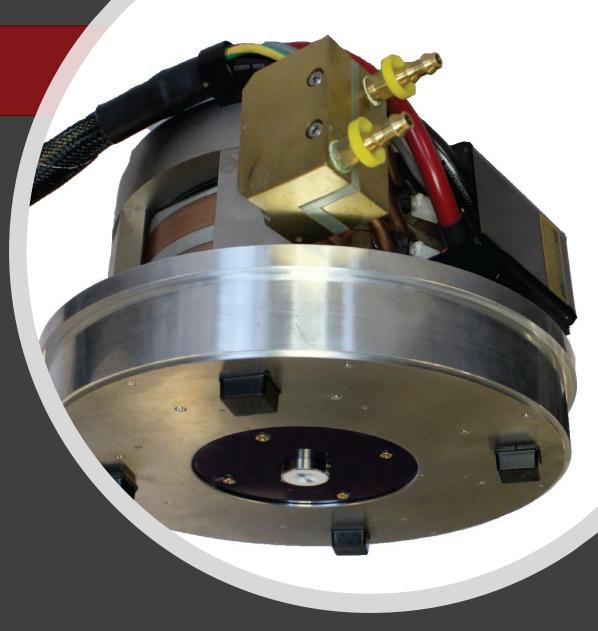
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How integration takes the work out of in-field testing

GMWAssociates

GMW and Celadon Prober Integration

- Spintronic On-Wafer testing facilitated by projected field magnets
- Integrating magnet and probe card requires both products to be compatible
- Customized magnetic field and contact configuration make compatibility difficult
- GMW and Celadon work together to make the solution to customer specification





GMW and Celadon Prober Integration

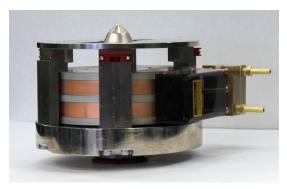




	5201 35A triangle 20A DC	5203 100A triangle 63A DC	5207 60A triangle 35A DC
Maximum Instantaneous Field	Optimized to	~2T	~2T
for a Single Device	order		
Maximum Instantaneous Field	0.50T	0.52T	>1T
for a 4mm Array	No extensions		
Maximum Continuous Field	Optimized to	1.68T	1.9T
for a Single Device	order		
Maximum Continuous Field	0.40T	0.38T	0.77T
for a 4mm Array	No extensions		

5203 Out-of-plane field 2.5 kg 74x74mm footprint

5201 In-plane field 2.5 kg 74x74mm footprint



5207 Out-of-plane field 20 kg Ø200mm footprint



GMW and Celadon Prober Integration



Spintronic On-Wafer Testing - An integrated Solution



Magnetic Configurations

Field Profiles and Field Shaping Getting the right solution

GMWAssociates

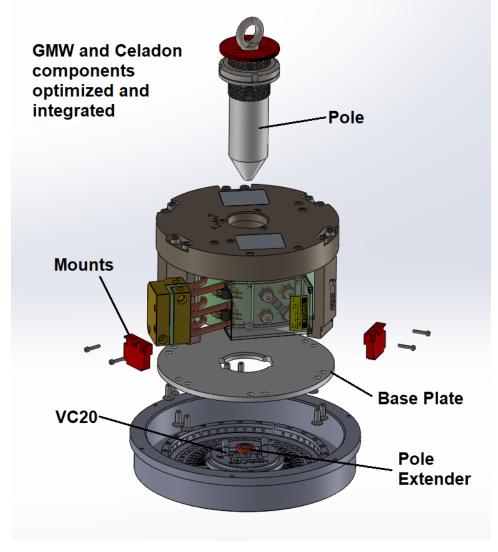
Configurable Magnetic Solutions





Spintronic On-Wafer Testing - An integrated Solution

Configurable Magnetic Solutions







Spintronic On-Wafer Testing - An integrated Solution

Two Industry Solutions MRAM Test

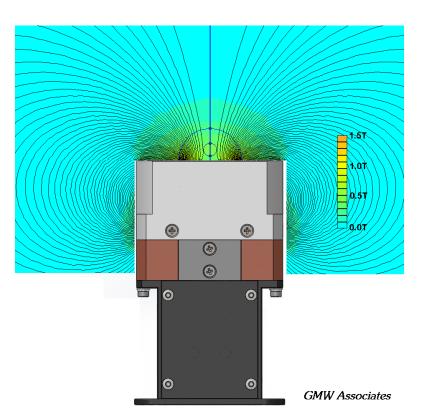
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Parametric and Functional Array Testing

5203 used for MRAM test over 4mm square array.

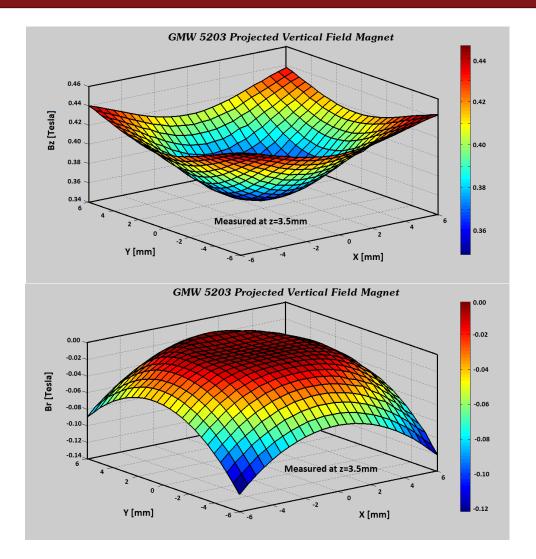
Requirements:

- >0.5T Out-of-Plane field Field sweep Triangle Waveform
- ~0.35T Out-of-Plane field Static continuous field
- Array 3.5mm from magnet pole to allow for contacts
- <1% In-Plane Field
- ~1% Field variation over 4mm square MRAM array
- Weight <3kg to allow for magnet and microscope interchange





Parametric and Functional Array Testing



Solution provides a static field of 0.38Tesla or a swept field of amplitude 0.52 Tesla. The amplitude variation over the array is a few percent.

The more strict criterion is for the array to experience the minimum possible in-plane field during test. The in-plane field is kept to within 10 Gauss over the whole array.

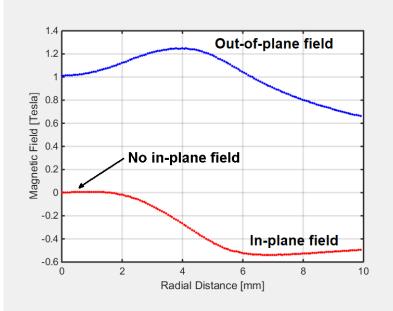


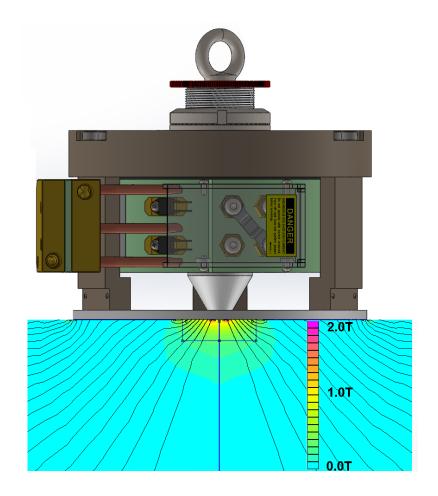
Spintronic On-Wafer Testing - An integrated Solution

Spintronic Device Test

5207 used for Spintronic test over 2x3mm array.

- >1T peak field (Triangle Waveform)
- Very low tolerance for in-plane field < 2mT
- Sample 1mm from pole (no contacts)
- Magnet is permanently in place, weight <20kg





GMWAssociates

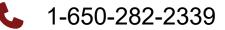
Thank You!



Tom King

Email: tom@gmw.com

www.gmw.com







Questions?

Please enter any questions into the chat box, thank you!

